



Date Created: 3/16/2004
Date Issued: 3/28/2004
PCN # 20041102

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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PCN Type: Alternate Assembly/Test Location/Qualification

Effectivity

Expected 1st Device Shipment Date: 6/24/2004
Earliest Year/Work Week of Changed Product: 0426
(Note: Package marking may differ from this format)

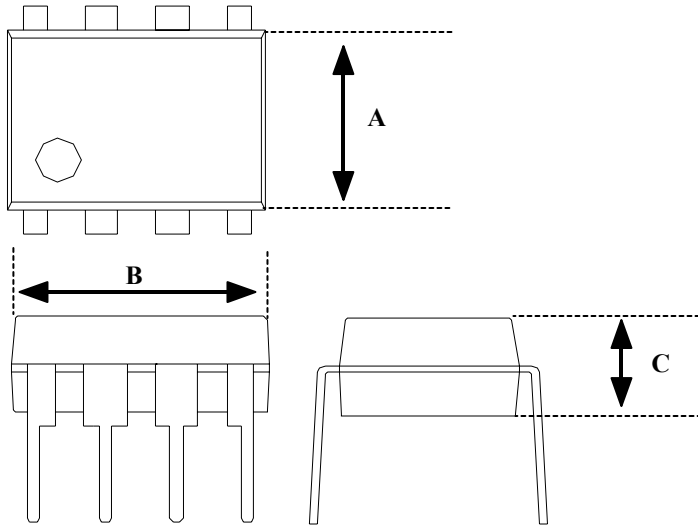
Product ID (Description):

FSDM0365RN, FSDL0365RN, FSDM0265RN, FSDH0265RN, FSDL0165RN, FSDM311, FSDL312 of 8pin-DIP
FSD210H of 8pin-DIPH

Description of Change:

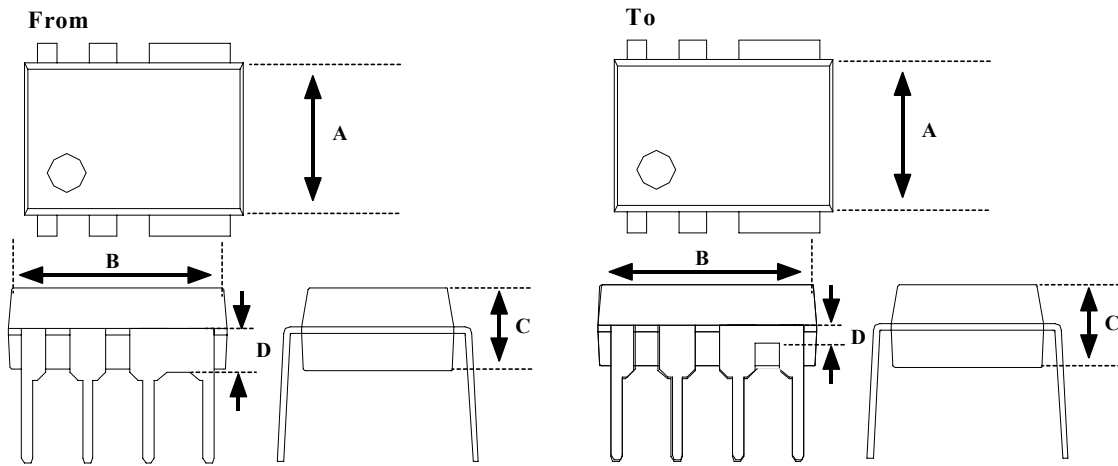
Fairchild Semiconductor's subcontractor, Hana electronics will be qualified as an alternative assembly and test site for Fairchild's 8-pin DIP and 8-pin DIPH packages. These packages will be qualified for production in Hana electronics with Pb-free plating. This product will also continue to be assembled and tested by the currently qualified supplier, SZEC in China. As previously noted in PCN# 20032701, SZEC will also be converting to Pb-free plating. The current schedule is such that at the time these products are approved for shipment from Hana, there will be no differences in assembly materials, plating or packing materials, except package outline dimensions.

*** 8DIP**



Unit:mm	From	To
A	6.40±0.2	6.57±0.05
B	Max 9.6	9.50±0.05
C	3.40±0.05	3.30±0.05

*** 8DIPH**



Unit:mm	From	To
A	6.40±0.2	6.57±0.05
B	Max 9.6	9.50±0.05
C	3.40±0.05	3.30±0.05
D	1.85	0.85

Effect of Change:

This change will not affect any electrical characteristics & reliability. The change will enlarge the production capacity to meet customer's needs. There is no difference in assembly materials or packing materials.

Under Fairchild's control, the same program will be applied to test the products from the Hana electronics.

Qualification:

The qualification plan is intended to meet our criteria for qualifying an alternate assembly & test site, the overall quality and reliability of our products.

Qual/REL Plan Numbers

Additional Qualification Data

*** 8DIP PKG QUAL PLAN(Only Official Qual lots) with FSDL0365RN**

	Test Conditions		
HTRB	Vdd=520V, Ta=125□	77 ea	168,500,1000HR
HTOL	Vdd=100V, Vcc=17V, Vstr=400V, Ta=125□	77 ea	168,500,1000HR
HTSL	Ta= 150□	77 ea	168,500,1000HR
THBT	85□/ 85%, Vcc= 15V->10V	77 ea	168,500,1000HR
TMCL	-65□ ~ +150□	77 ea	200,500CL
ACLV	Ta=121□, RH=100%, Pressure=15 PSIG	77 ea	96HR
Dynamic	Vin=220Vac	30 ea	96HR

*** 8DIPH PKG QUAL PLAN(Only Official Qual lots) with FSD210H**

	Test Conditions		
HTRB	Vdd=560V, Ta=125□	77 ea	168,500,1000HR
HTOL- JFET	Vstr=560V, Ta=125□	77 ea	168,500,1000HR
HTOL	Vdd=100V, Vcc=17V, Vstr=400V, Ta=125□	77 ea	168,500,1000HR
HTSL	Ta= 150□	77 ea	168,500,1000HR
THBT	85□/ 85%, Vcc= 15V->10V	77 ea	168,500,1000HR
TMCL	-65□ ~ +150□	77 ea	200,500CL
ACLV	Ta=121□, RH=100%, Pressure=15 PSIG	77 ea	96HR
Dynamic	Vin=220Vac	30 ea	96HR

Affected FSIDs

FSD210H
FSDL0365RN
FSDM0365RN

FSDH0265RN
FSDL312
FSDM311

FSDL0165RN
FSDM0265RN